## Notice of References Cited Application/Control No. 10/758,255 DE BAST ET AL. Examiner Terence Boes Applicant(s)/Patent Under Reexamination DE BAST ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,282,984	09-2001	Chen, Chung-I	74/594.6
*	В	US-6,908,159	06-2005	Prince et al.	297/452.23
*	С	US-2003/0029271	02-2003	Shuman, Derek Barnet	74/594.6
*	D	US-5,195,397	03-1993	Nagano, Masashi	74/594.4
.*	Ε	US-6,536,304	03-2003	Peyre, Henri	74/594.6
*	F	US-5,031,263	07-1991	Babb et al.	15/104.33
*	G	US-2002/0050773	05-2002	Reis, Norbert	312/334.46
*	Н	US-6,012,356	01-2000	Ueda, Yutaka	74/594.6
*	_	US-6,196,084	03-2001	Ueda, Yutaka	74/594.6
*	J	US-2002/0066337	06-2002	Bryne, Richard M.	74/594.6
	К	US-			
	L	US-		·	
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	FR002809701	12-2001	France	Lancelot, Michel;Pecqueux	B62m3/08
	0					
	Р					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	v						
	w						
	x	s. Ner					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.